Search Notes

	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/725,132	ONISHI	
٠	Examiner	Art Unit	
	Len Tran	1725	

	SEARCHED				
Class	Subclass	Date	Examiner		
219	109	3/6/2005	LT		
	86.9				
	56.22				
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
211	ABON	1/10/06	U			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST and Palm	3/6/2005	LT		
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